

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices – Mechanical and climatic test methods –
Part 12: Vibration, variable frequency**

**Dispositifs à semiconducteurs – Méthodes d’essais mécaniques et climatiques –
Partie 12: Vibrations, fréquences variables**





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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES – MECHANICAL
AND CLIMATIC TEST METHODS –**
Part 12: Vibration, variable frequency**FOREWORD**

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International Standard IEC 60749-12 has been prepared by IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2002. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) alignment with MIL-STD-883J Method 2007, Vibration, variable frequency.

The text of this International Standard is based on the following documents:

CDV	Report on voting
47/2386/CDV	47/2434/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

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